

## **Search Notes**



**Application/Control No.**

10/709,716

**Examiner**

Anh T.N. Vo

**Applicant(s)/Patent under  
Reexamination**

LEE ET AL.

## **Art Unit**

2861

**SEARCHED**

# **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner